

**Search Notes**

Application/Control No.

10/617,771

Examiner

EDMUND H. LEE

Applicant(s)/Patent under  
Reexamination

KRALIK ET AL.

Art Unit

1791

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
<b>264</b>	<b>257,163</b>	10/1/2008	<b>EHL</b>
	275,135	10/1/2008	EHL
	136	10/1/2008	EHL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
UPDATED	10/1/2008	EHL
264/257,163,275,135,136	10/1/2008	EHL